

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination
	09/682,890	DEWANJEE ET AL.
	Examiner EDMUND H. LEE	Art Unit 1732

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,688,191	11-1997	Cavallaro et al.	473/373
	B	US-5,908,358	06-1999	Wu, Shenshen	473/378
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N	JP 10-33716 A	02-1998	JP	Maruoka et al	-----
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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